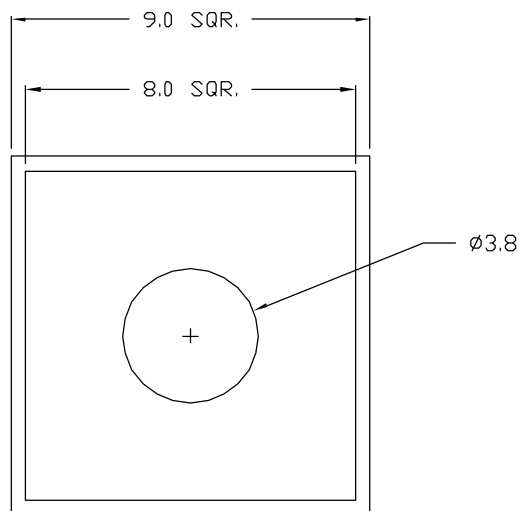


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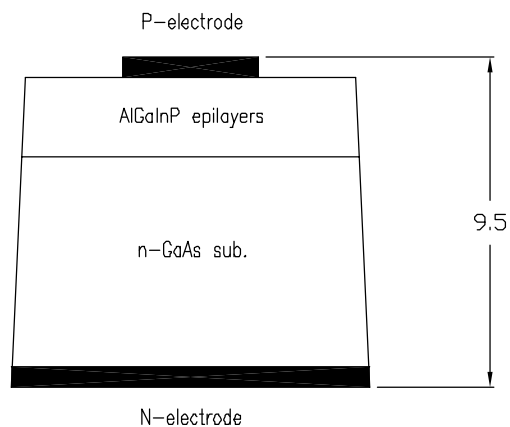
SSD-LX009E587FGPU

REV.



ELECTRO-OPTICAL CHARACTERISTICS:

PARAMETER	SYMBOL		TEST COND	MIN	TYP	MAX	UNITS
FORWARD VOLTAGE	V _{f1}		I _f =10μA	1.35			V
	V _{f2}		I _f =20mA		2.0	2.4	V
REVERSE CURRENT	I _r		V _r =10V			100	μA
PEAK WAVELENGTH	λ _p		I _f =20mA		591		nm
DOMINANT WAVELENGTH ⁽¹⁾	λ _d		I _f =20mA	586	587	588	nm
SPECTRA HALF-WIDTH	Δλ		I _f =20mA		15		nm
LUMINOUS INTENSITY ⁽²⁾	I _v	A4	I _f =20mA	50	I _v (ave.) ⁽²⁾ ≥ 60		mcd
		A5		60	I _v (ave.) ⁽²⁾ ≥ 75		
		A6		75	I _v (ave.) ⁽²⁾ ≥ 100		

(1) Basically, wavelength uniformity is $\lambda_d \pm 5nm$.(2) $I_v(ave.)$ is the average luminous intensity of overall qualified chips from individual epiwafer.

NOTE:

UNITS: mil

CAUTION: STATIC SENSITIVE DEVICE
FOLLOW PROPER E.S.D. HANDLING PROCEDURES
WHEN WORKING WITH THIS PART.

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587nm CHIP

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RELIABILITY NOTE

OUR MANY YEARS OF EXPERIENCE DATA ACCUMULATION INDICATE THAT SOLDER HEAT IS A MAJOR CAUSE OF EARLY AND FUTURE FAILURE. PLEASE PAY ATTENTION TO YOUR SOLDERING PROCESS.

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SCALE: N/A